

Top-seeded solution growth and characterization of β -Ga₂O₃

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Table S1. Crystallographic Data and Structural Refinements for β -Ga₂O₃.

Empirical formula	Ga ₂ O ₃
Formula weight	374.88
Temperature (K)	273
Crystal system	Monoclinic
Space group	<i>C2/m</i>
<i>a</i> (Å)	12.247(10)
<i>b</i> (Å)	3.044(2), β =103.866(4)°
<i>c</i> (Å)	5.813(5)
Volume(Å ³)	210.41(3)
<i>Z</i>	2
<i>D_c</i> (g cm ⁻³)	5.917
μ (mm ⁻¹)	24.279
<i>F</i> (000)	334
Completeness to theta	99.6%
GOF on <i>F</i> ²	1.042
<i>R_I</i> , <i>wR</i> ₂ (<i>I</i> > 2σ(<i>I</i>)) ^a	0.0221, 0.0513
<i>R_I</i> , <i>wR</i> ₂ (all data)	0.0282, 0.0542
Largest diff. peak and hole (eÅ ⁻³)	0.781 and -0.763

^[a] $R_1 = \sum ||F_o| - |F_c|| / \sum |F_o|$ and $wR_2 = [\sum w(F_o^2 - F_c^2)^2 / \sum w F_o^4]^{1/2}$ for $F_o^2 > 2\sigma(F_o^2)$

Table S2. Atomic coordinates and equivalent isotropic atomic displacement parameters (Å²), bond valence sums (BVSs) for β -Ga₂O₃.

Atom	x/a	y/b	z/c	U(eq)	BVS
Ga1	0.40951(5)	0.5	0.70552(11)	0.0062(2)	2.92
Ga2	0.65866(5)	0	0.81391(11)	0.0061(2)	2.94
O1	0.3264(3)	0.5	0.9365(7)	0.0055(8)	1.93
O2	0.3354(4)	0.5	0.3910(8)	0.0090(8)	1.87
O3	0.4963(3)	0	0.7566(8)	0.0098(9)	2.06

Table S3. Selected Bond Distances (Å) and Angles (°) for β -Ga₂O₃.

Atom–Atom	Length [Å]	Atom–Atom–Atom	Angle [°]
Ga1–O2	1.836(5)	O3–Ga1–O1	106.08(14)
Ga1–O3	1.839(2)	O3–Ga2–O2#7	94.71(15)
Ga2–O3	1.936(4)	O3–Ga2–O1#4	169.43(17)

Ga2-O2#5	1.945(3)	O2#7-Ga2-O1#4	91.85(15)
Ga2-O1#6	2.080(3)	O2#5-Ga2-O1#8	171.80(18)
Ga1-O2	1.836(5)	O1#4-Ga2-O1#8	80.82(11)
Ga1-O3	1.839(2)	O2#5-Ga2-O1#6	81.06(13)
Ga2-O3	1.936(4)	O1#4-Ga2-O1#6	80.82(11)
Ga2-O2#5	1.945(3)	O2-Ga1-O3#2	106.82(16)
Ga2-O1#6	2.080(3)	O3#2-Ga1-O3	111.7(2)
Ga1-O2	1.836(5)	O3#2-Ga1-O1	106.08(14)
Ga1-O3	1.839(2)	O3-Ga2-O2#5	94.71(15)
Ga2-O3	1.936(4)	O2#5-Ga2-O2#7	103.0(2)
Ga2-O2#5	1.945(3)	O2#5-Ga2-O1#4	91.85(15)
Ga2-O1#6	2.080(3)	O3-Ga2-O1#8	92.02(14)
Ga1-O2	1.836(5)	O2#7-Ga2-O1#8	81.06(13)
Ga1-O3	1.839(2)	O3-Ga2-O1#6	92.02(14)
Ga2-O3	1.936(4)	O2#7-Ga2-O1#6	171.80(18)
Ga2-O2#5	1.945(3)	O1#8-Ga2-O1#6	94.04(16)
Ga2-O1#6	2.080(3)	O2-Ga1-O3	106.82(15)
O2-Ga1-O1	119.41(19)		

Symmetry transformations used to generate equivalent atoms:

#1 $x, y-1, z$ #2 $x, y+1, z$ #3 $x-1/2, y+1/2, z$ #4 $x+1/2, y-1/2, z$
#5 $-x+1, -y, -z+1$ #6 $-x+1, -y, -z+2$ #7 $-x+1, -y+1, -z+1$ #8 $-x+1, -y+1, -z+2$

Table S4. The full-width at half maximum (FWHM) comparison of β -Ga₂O₃ by different methods.

Compound	Methods of crystal growth	FWHM	Ref.
β -Ga ₂ O ₃	the floating zone technique (OFZ)	324"	1
β -Ga ₂ O ₃	edge-defined film-fed growth (EFG)	90"	2
β -Ga ₂ O ₃	OFZ	100"	3
β -Ga ₂ O ₃	OFZ	108"	4
β -Ga ₂ O ₃	Czochralski (CZ)	36"	5
β -Ga ₂ O ₃	EFG	59.4"	6
β -Ga ₂ O ₃	EFG	69.3"	7
β-Ga₂O₃	TSSG	140.04"	This work

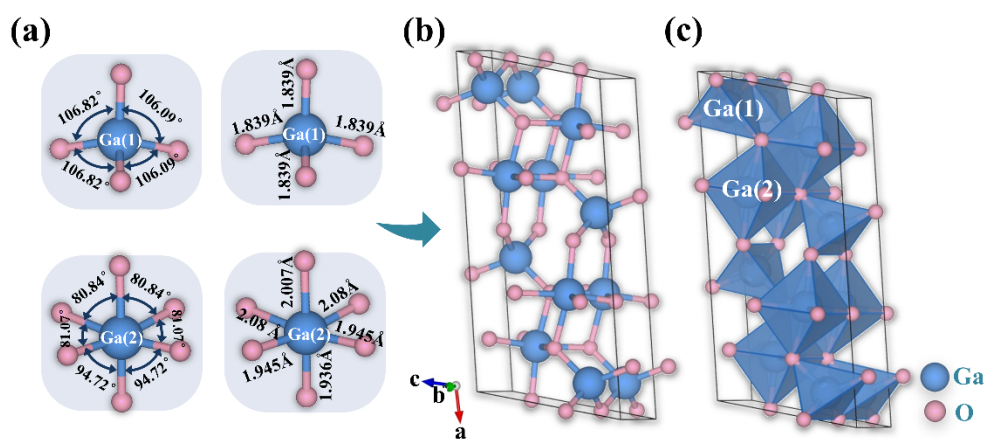


Fig. S1. (a) Complete coordination environment of cations in β -Ga₂O₃, (b) Ball-and-stick representation of the unit cell of β -Ga₂O₃ crystal structure along the b-axis, and (c) polyhedral representation of the β -Ga₂O₃ crystal structure.

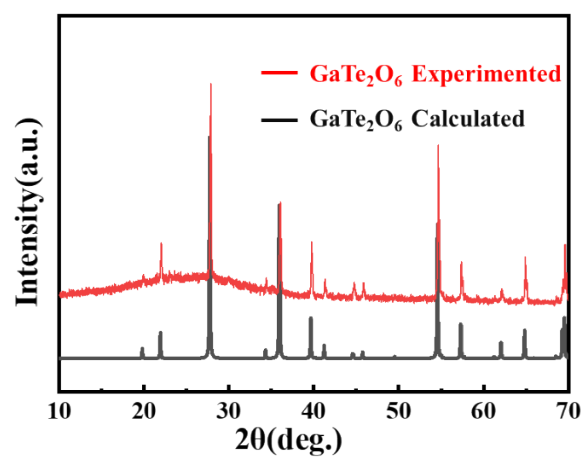


Fig. S2. The powder X-ray diffraction pattern of GaTe₂O₆ crystal (sticking on the rod).

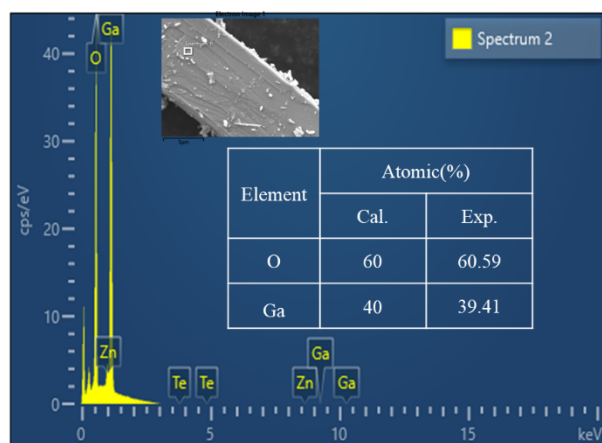


Fig. S3. The EDS spectra of β -Ga₂O₃ crystal.

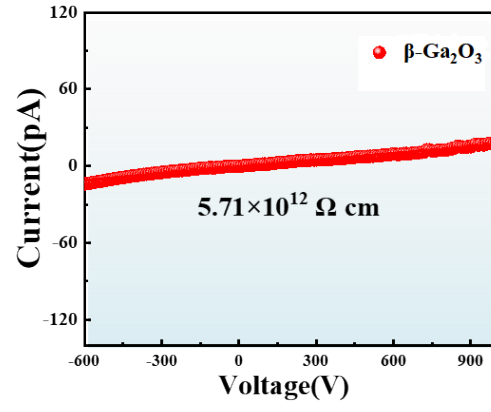


Fig. S4. I-V curves for resistivity measurements of $\beta\text{-Ga}_2\text{O}_3$ crystal.

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